







TEXAS

01

STI Process

- Now the dominant isolation approach
- Uses less area, allowing greater transistor density
- Trench depth can be large (~500nm) even as trench width decreases
- Requires well controlled deep etches, good oxide CVD process, and CMP
 CMR Mark, 2013



TEXAS

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Lecture 27: What have we learned?

- Why is device isolation needed?
- What are the two most common device isolation processes?
- Why is STI the more common today?